VND830ASP-E

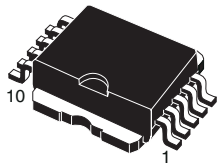
Double channel high-side solid state relay

Features

Type	$R_{DS(on)}$	I_{OUT}	V_{CC}
VND830ASP-E	60 mΩ	6 A(1)	36 V(1)

1. Per channel

- ECOPACK®: lead free and RoHS compliant
- Automotive Grade: compliance with AEC guidelines
- Very low standby current
- CMOS compatible input
- Proportional load current sense
- Current sense disable
- Thermal shutdown protection and diagnosis
- Undervoltage shutdown
- Overvoltage clamp
- Load current limitation



PowerSO-10

Description

The VND830ASP-E is a monolithic device made using STMicroelectronics™ VIPower™ M0-3 technology. It is intended for driving any kind of load with one side connected to ground. Active V_{CC} pin voltage clamp protects the device against low energy spikes (see ISO7637 transient compatibility table).

This device has two channels in high-side configuration; each channel has an analog sense output on which the sensing current is proportional (according to a known ratio) to the corresponding load current.

Built-in thermal shutdown and outputs current limitation protect the chip from overtemperature and short circuit. Device turns-off in case of ground pin disconnections.

Table 1. Device summary

Package	Order codes	
	Tube	Tape and reel
Power-SO-10™	VND830ASP-E	VND830ASPTR-E

Contents

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1 Block diagram and pin description

Figure 1. Block diagram

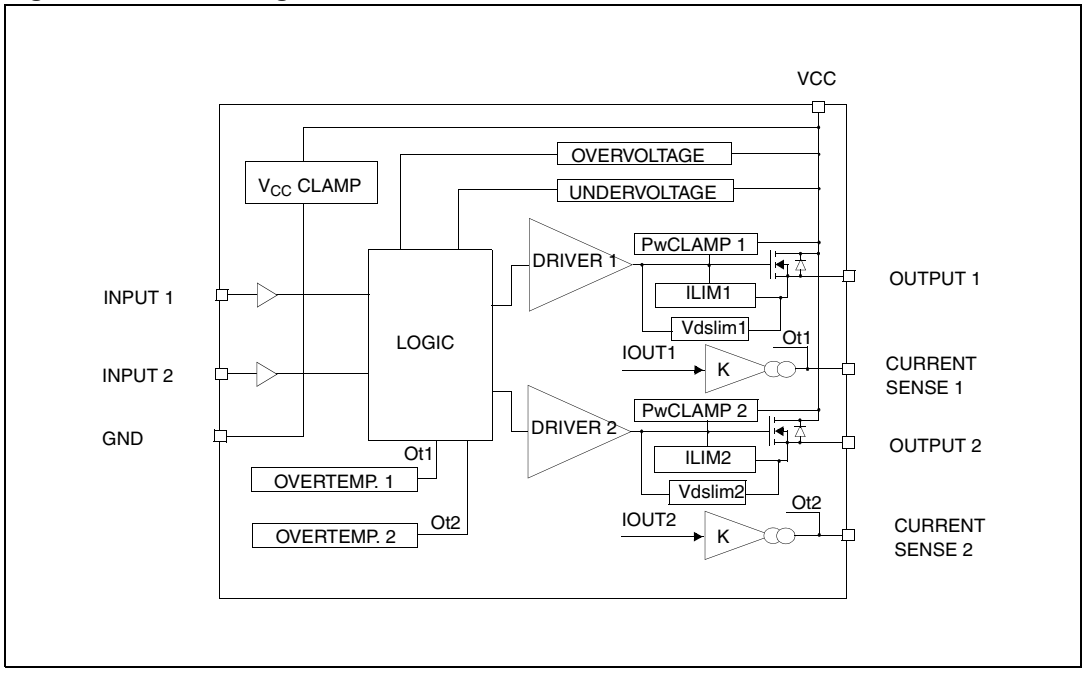
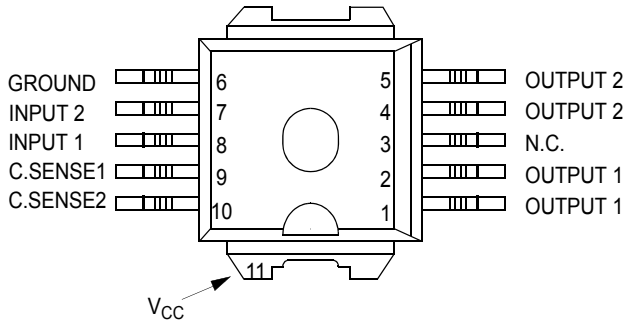


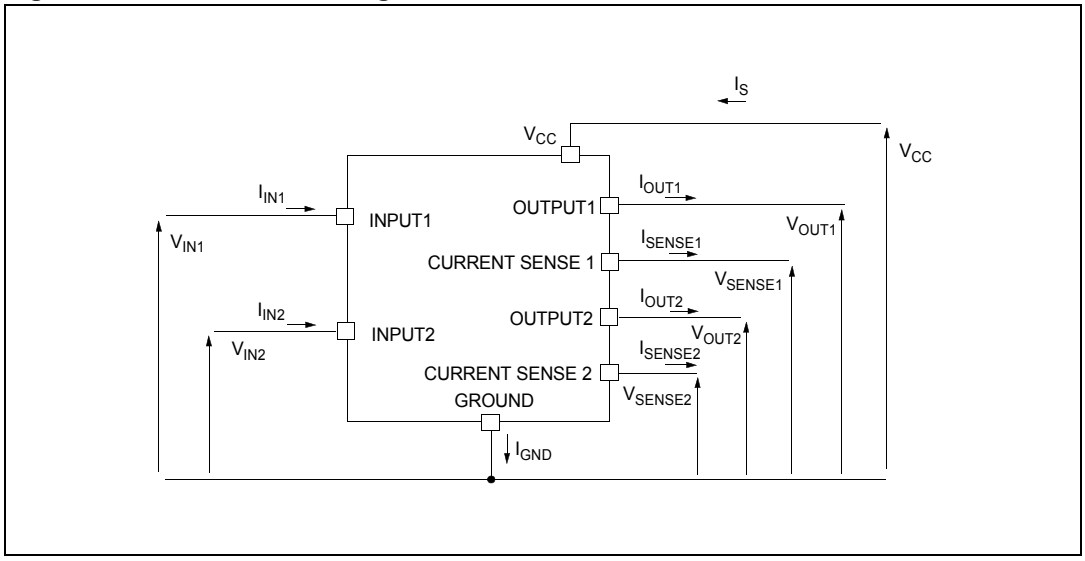
Figure 2. Configuration diagram (top view)



PowerSO-10

2 Electrical specifications

Figure 3. Current and voltage conventions



2.1 Absolute maximum ratings

Stressing the device above the rating listed in *Table 2* may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics sure program and other relevant quality document.

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CC}	DC supply voltage	41	V
$-V_{CC}$	Reverse supply voltage	-0.3	V
$- I_{GND}$	DC reverse ground pin current	-200	mA
I_{OUT}	Output current	Internally limited	A
I_R	Reverse output current	-6	A
I_{IN}	Input current	+/- 10	mA
V_{CSENSE}	Current sense maximum voltage	-3 +15	V V

Table 2. Absolute maximum ratings (continued)

Symbol	Parameter	Value	Unit
V_{ESD}	Electrostatic discharge (Human Body Model: R = 1.5 Ω; C = 100 pF) – INPUT – CURRENT SENSE – OUTPUT – V_{CC}	 4000 2000 5000 5000	 V V V V
E_{MAX}	Maximum switching energy (L = 1.8 mH; R_L = 0 Ω; V_{bat}= 13.5 V; T_{jstart} = 150 °C; I_L = 9 A)	100	mJ
P_{tot}	Power dissipation at T_c = 25 °C	74	W
T_j	Junction operating temperature	Internally limited	°C
T_c	Case operating temperature	-40 to 150	°C
T_{STG}	Storage temperature	-55 to 150	°C

2.2 Thermal data

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj\text{-}case}$	Thermal resistance junction-case	1.3	°C/W
$R_{thj\text{-}amb}$	Thermal resistance junction-ambient	51.2(1)	°C/W

1. When mounted on a standard single sided FR-4 board with 0.5 cm^2 of Cu (at least 35 µm thick). Horizontal mounting and no artificial air flow.

2.3 Electrical characteristics

Values specified in this section are for 8 V < V_{CC} < 36 V; -40 °C < T_j < 150 °C, unless otherwise specified. (Per each channel).

Table 4. Power

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V_{CC}	Operating supply voltage		5.5	13	36	V
V_{USD}	Undervoltage shutdown		3	4	5.5	V
V_{OV}	Overvoltage shutdown		36			V
R_{ON}	On-state resistance	I_{OUT} = 2 A; T_j = 25 °C			60	mΩ
		I_{OUT} = 2 A; T_j = 150 °C			120	mΩ
V_{clamp}	Clamp voltage	I_{CC} = 20 mA(1)	41	48	55	V
I_S	Supply current	Off-state; V_{CC} = 13 V; V_{IN} = V_{OUT} = 0 V		12	40	µA
		Off-state; V_{CC}=13V; V_{IN} = V_{OUT} = 0 V; T_j = 25 °C		12	25	µA
		On-state; V_{IN} = 5 V; V_{CC} = 13 V; I_{OUT} = 0 A; R_{SENSE} = 3.9 kΩ			7	mA
$I_{L(off1)}$	Off-state output current	V_{IN} = V_{OUT} = 0 V; V_{CC} = 36 V; T_j = 125 °C	0		50	µA
$I_{L(off2)}$	Off-state output current	V_{IN} = 0 V; V_{OUT} = 3.5 V	-75		0	µA
$I_{L(off3)}$	Off-state output current	V_{IN} = V_{OUT} = 0 V; V_{CC} = 13 V; T_j = 125 °C			5	µA
$I_{L(off4)}$	Off-state output current	V_{IN} = V_{OUT} = 0 V; V_{CC} = 13 V; T_j = 25 °C			3	µA

1. V_{clamp} and V_{OV} are correlated. Typical difference is 5 V.

Table 5. Switching (V_{CC} = 13 V)

Symbol	Parameter	Test conditions	Min	Typ	Max	Unit
$t_{d(on)}$	Turn-on delay time	R_L = 6.5 Ω from V_{IN} rising edge to V_{OUT} = 1.3 V	-	30	-	µs
$t_{d(off)}$	Turn-on delay time	R_L = 6.5 Ω from V_{IN} falling edge to V_{OUT} = 11.7 V	-	30	-	µs
$(dV_{OUT}/dt)_{on}$	Turn-on voltage slope	R_L = 6.5 Ω from V_{OUT} = 1.3 V to V_{OUT} = 10.4 V	-	See *Figure 15*	-	V/µs
$(dV_{OUT}/dt)_{off}$	Turn-off voltage slope	R_L = 6.5 Ω from V_{OUT} = 11.7 V to V_{OUT} = 1.3 V	-	See *Figure 16*	-	V/µs

Table 6. Logic input (channel 1, 2)

Symbol	Parameter	Test conditions	Min	Typ	Max	Unit
V_{IL}	Input low level voltage				1.25	V
I_{IL}	Low level input current	V_{IN} = 1.25 V	1			µA
V_{IH}	Input high level voltage		3.25			V
I_{IH}	High level input current	V_{IN} = 3.25 V			10	µA
$V_{I(hyst)}$	Input hysteresis voltage		0.5			V
V_{ICL}	Input clamp voltage	I_{IN} = 1 mA	6	6.8	8	V
		I_{IN} = -1 mA		-0.7		V

Table 7. V_{CC} - output diode

Symbol	Parameter	Test conditions	Min	Typ	Max	Unit
V_F	Forward on voltage	$-I_{OUT}$ = 2 A; T_j = 150 °C	-	-	0.6	V

Table 8. Protection

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{lim}	DC short circuit current	V_{CC} = 13 V	6	9	15	A
		5.5 V < V_{CC} <36 V			15	A
T_{TSD}	Thermal shutdown temperature		150	175	200	°C
T_R	Thermal reset temperature		135			°C
T_{HYST}	Thermal hysteresis		7	15		°C
V_{demag}	Turn-off output voltage clamp	I_{OUT} = 2 A; V_{IN} = 0 V; L = 6 mH	V_{CC}-41	V_{CC}-48	V_{CC}-55	V
V_{ON}	Output voltage drop limitation	I_{OUT} = 10 mA		50		mV

Table 9. Current sense(1)

Symbol	Parameter	Test conditions	Min	Typ	Max	Unit
K_0	I_{OUT}/I_{SENSE}	I_{OUT1} or I_{OUT2} = 0.05 A; V_{SENSE} = 0.5 V; other channels open; T_j = -40 °C...150 °C	600	1300	2000	
K_1	I_{OUT}/I_{SENSE}	I_{OUT1} or I_{OUT2} = 0.25 A; V_{SENSE} = 0.5 V; other channels open; T_j = -40 °C...150 °C	1000	1400	1900	
dK_1/K_1	Current sense ratio drift	I_{OUT1} or I_{OUT2} = 0.25 A; V_{SENSE} = 0.5 V; other channels open; T_j = -40 °C...150 °C	-10		+10	%
K_2	I_{OUT}/I_{SENSE}	I_{OUT1} or I_{OUT2} = 1.6 A; V_{SENSE} = 4 V; other channels open; T_j = -40 °C T_j = 25 °C...150 °C	1280 1300	1500 1500	1800 1780	
dK_2/K_2	Current sense ratio drift	I_{OUT1} or I_{OUT2} = 1.6 A; V_{SENSE} = 4 V; other channels open; T_j = -40 °C...150 °C	-6		+6	%
K_3	I_{OUT}/I_{SENSE}	I_{OUT1} or I_{OUT2} = 2.5 A; V_{SENSE} = 4 V; other channels open; T_j = -40 °C T_j = 25 °C...150 °C	1280 1340	1500 1500	1680 1600	
dK_3/K_3	Current sense ratio drift	I_{OUT1} or I_{OUT2} = 2.5 A; V_{SENSE} = 4 V; other channels open; T_j = -40 °C...150 °C	-6		+6	%
I_{SENSE}	Analog sense leakage current	V_{IN} = 0 V; I_{OUT} = 0 A; V_{SENSE} = 0 V; T_j = -40 °C...150 °C	0		5	µA
		V_{IN} = 5 V; I_{OUT} = 0 A; V_{SENSE} = 0 V; T_j = -40 °C...150 °C	0		10	µA
V_{SENSE}	Max analog sense output voltage	V_{CC} = 5.5 V; $I_{OUT1,2}$ = 1.3 A; R_{SENSE} = 10 kΩ	2			V
		V_{CC} > 8 V, $I_{OUT1,2}$ = 2.5 A; R_{SENSE} = 10 kΩ	4			V
V_{SENSEH}	Sense voltage in overtemperature condition	V_{CC} = 13 V; R_{SENSE} = 3.9 kΩ		5.5		V
$R_{VSENSEH}$	Analog sense output impedance in overtemperature condition	V_{CC} = 13 V; T_j > T_{TSD}; All channels open		400		Ω
t_{DSENSE}	Current sense delay response	to 90% I_{SENSE} (2)			500	µs

1. 9 V ≤ V_{CC} ≤ 16 V (see *Figure 4*)
2. Current sense signal delay after positive input slope. Sense pin doesn't have to be left floating.

Figure 4. Switching characteristics (resistive load R_L = 6.5 Ω)

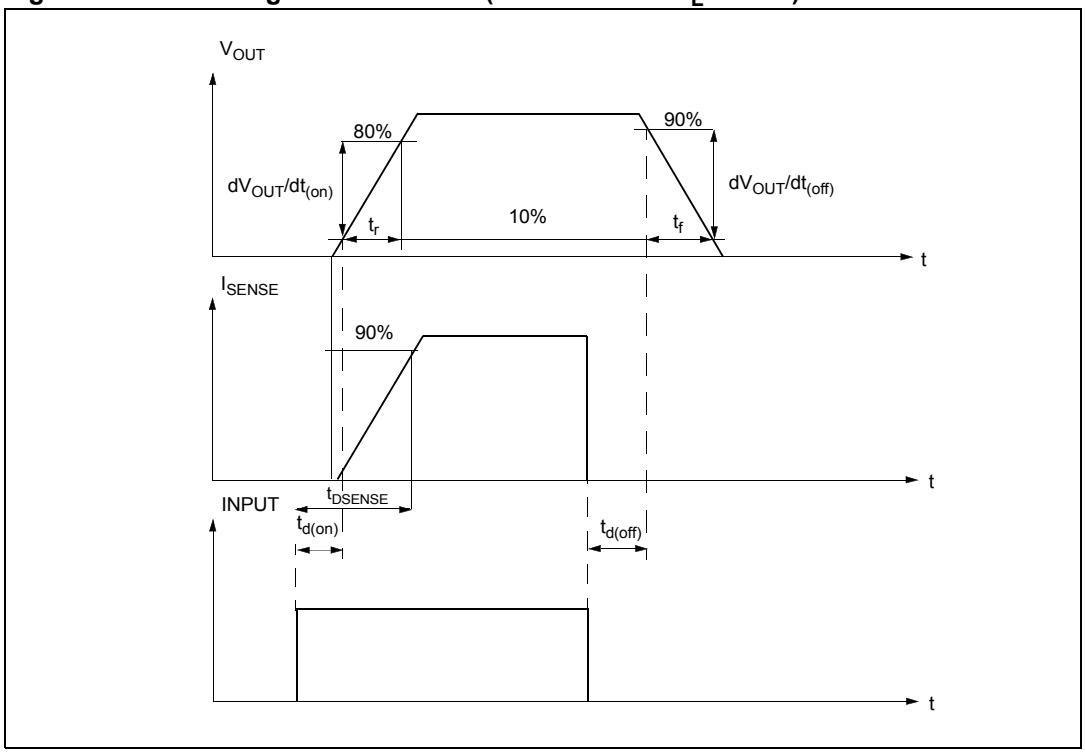
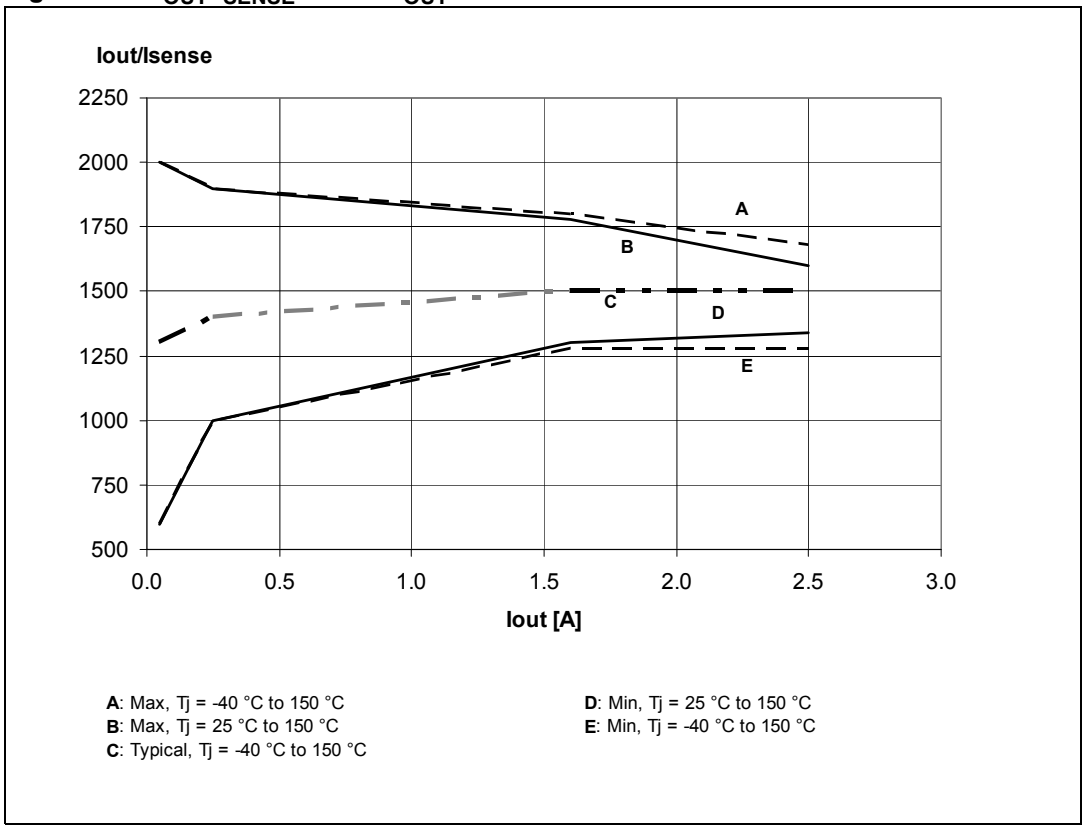


Figure 5. I_{OUT}/I_{SENSE} versus I_{OUT}



A: Max, Tj = -40 °C to 150 °C
B: Max, Tj = 25 °C to 150 °C
C: Typical, Tj = -40 °C to 150 °C
D: Min, Tj = 25 °C to 150 °C
E: Min, Tj = -40 °C to 150 °C

Table 10. Truth table (per each channel)

Conditions	Input	Output	Sense
Normal operation	L H	L H	0 Nominal
Overtemperature	L H	L L	0 V_{SENSEH}
Undervoltage	L H	L L	0 0
Overvoltage	L H	L L	0 0
Short circuit to GND	L H H	L L L	0 (T_j<T_{TSD}) 0 (T_j>T_{TSD}) V_{SENSEH}
Short circuit to V_{CC}	L H	H H	0 < Nominal
Negative output voltage clamp	L	L	0

Table 11. Electrical transient requirements on V_{CC} pin (part 1)

ISO T/R 7637/1 test pulse	Test levels				
	I	II	III	IV	Delays and impedance
1	-25 V	-50 V	-75 V	-100 V	2 ms, 10 Ω
2	+25 V	+50 V	+75 V	+100 V	0.2 ms, 10 Ω
3a	-25 V	-50 V	-100 V	-150 V	0.1 µs, 50 Ω
3b	+25 V	+50 V	+75 V	+100 V	0.1 µs, 50 Ω
4	-4 V	-5 V	-6 V	-7 V	100 ms, 0.01 Ω
5	+26.5 V	+46.5 V	+66.5 V	+86.5 V	400 ms, 2 Ω

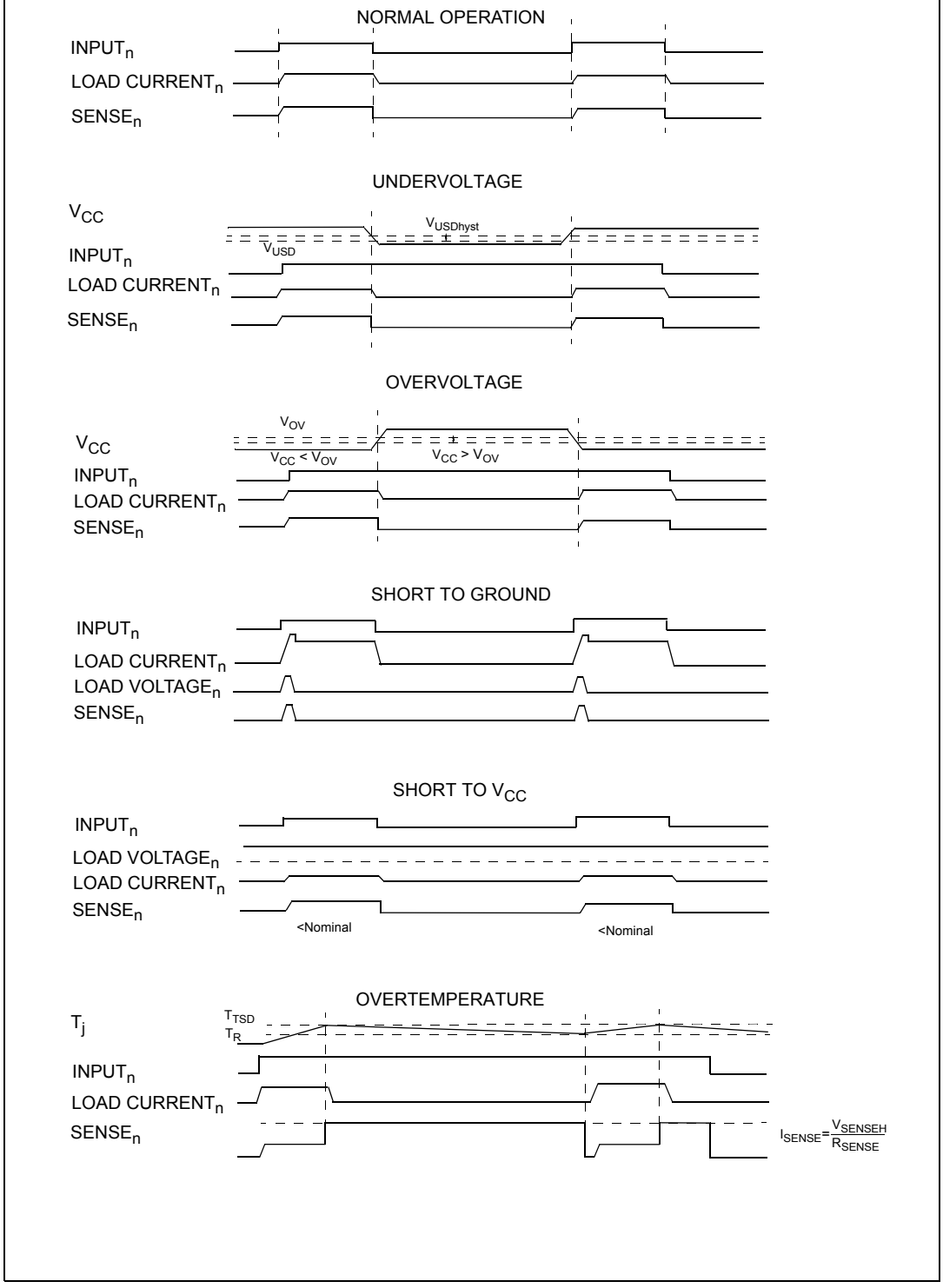
Table 12. Electrical transient requirements on V_{CC} pin (part 2)

ISO T/R 7637/1 Test pulse	Test levels results			
	I	II	III	IV
1	C	C	C	C
2	C	C	C	C
3a	C	C	C	C
3b	C	C	C	C
4	C	C	C	C
5	C	E	E	E

Table 13. Electrical transient requirements on V_{CC} pin (part 3)

Class	Contents
C	All functions of the device are performed as designed after exposure to disturbance.
E	One or more functions of the device is not performed as designed after exposure to disturbance and cannot be returned to proper operation without replacing the device.

Figure 6. Waveforms



2.4 Electrical characteristics curves

Figure 7. Off-state output current

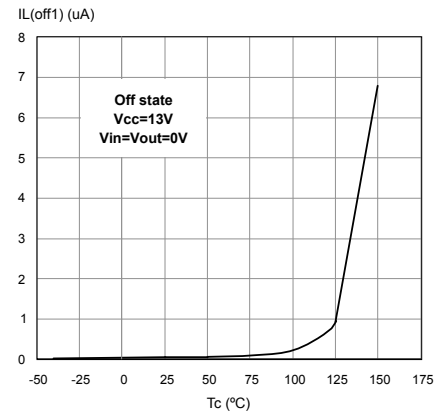


Figure 8. High level input current

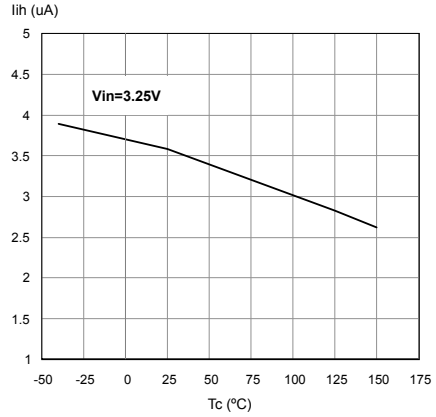


Figure 9. Input clamp voltage

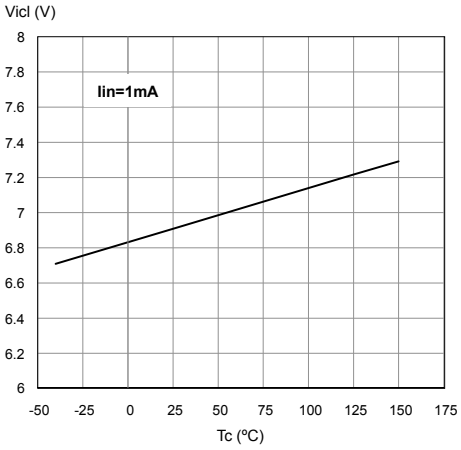


Figure 10. Input high level

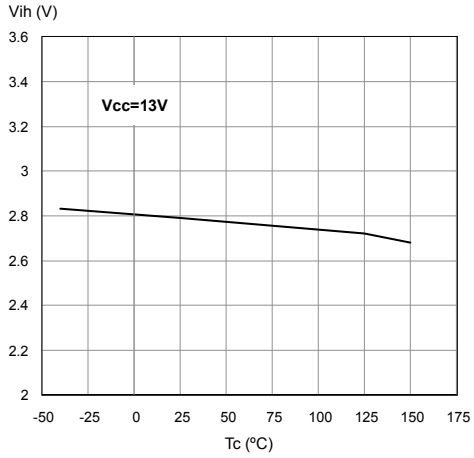


Figure 11. Input low level

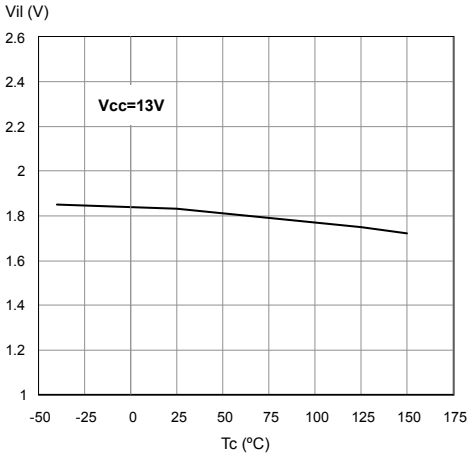


Figure 12. Input hysteresis voltage

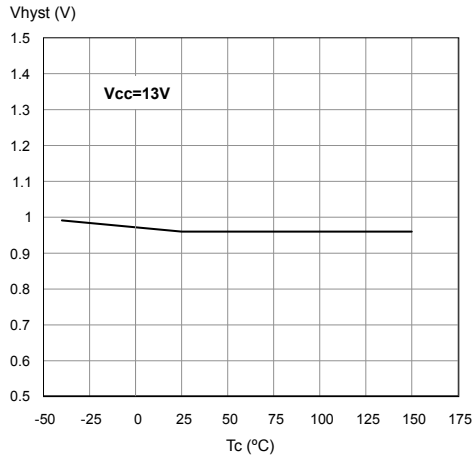


Figure 13. Overvoltage shutdown

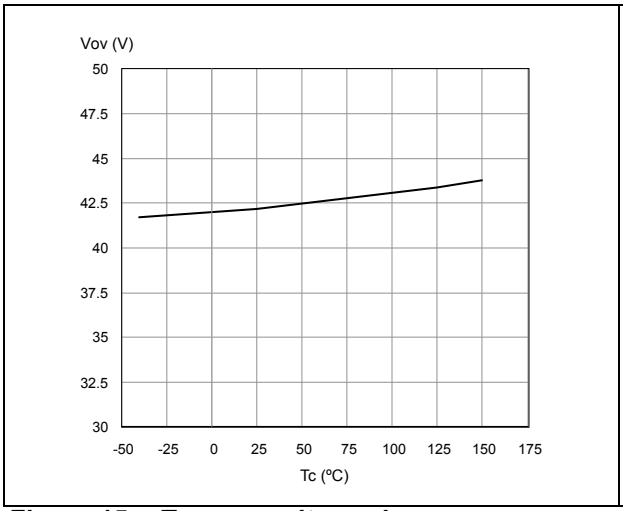


Figure 14. I_{LIM} vs T_{case}

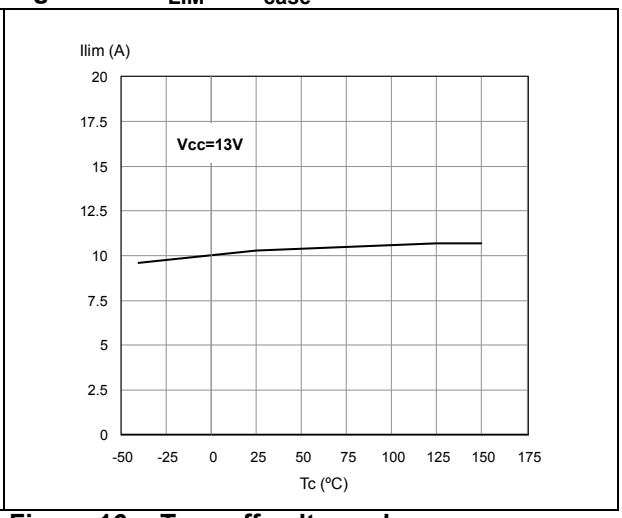


Figure 15. Turn-on voltage slope

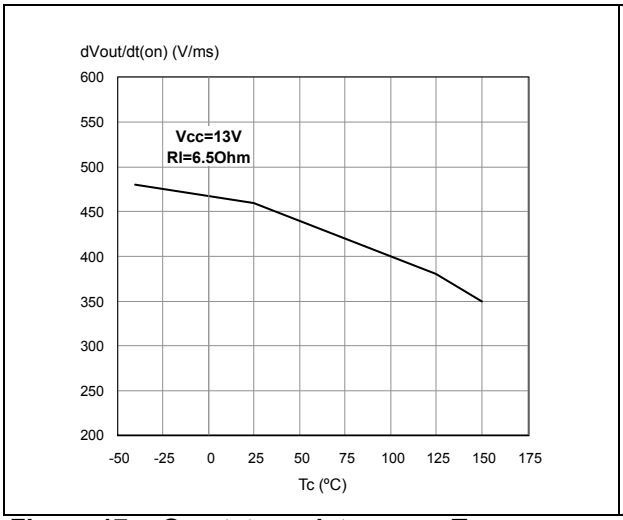


Figure 16. Turn-off voltage slope

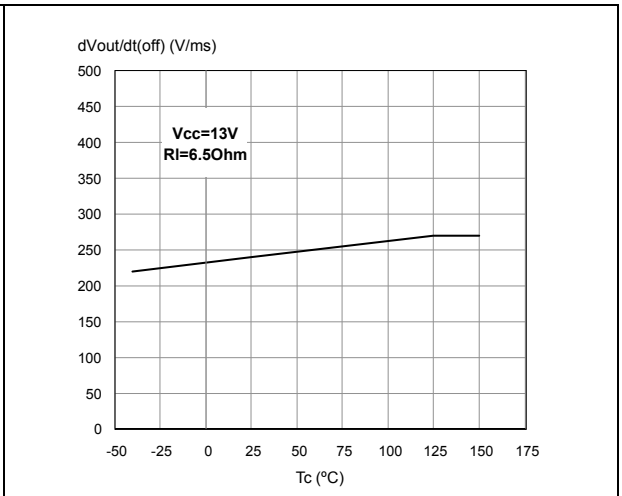


Figure 17. On-state resistance vs T_{case}

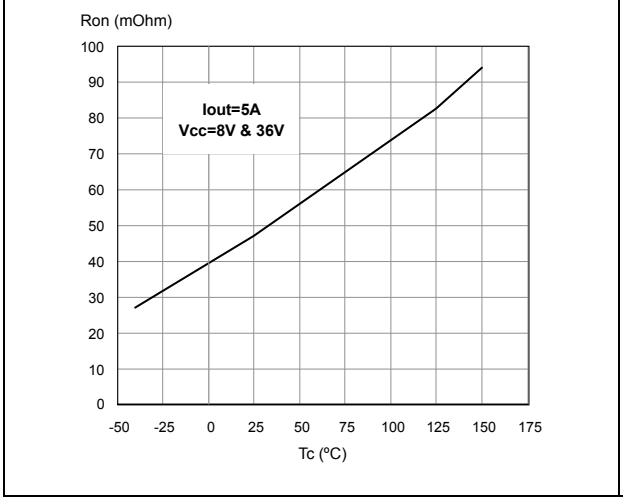
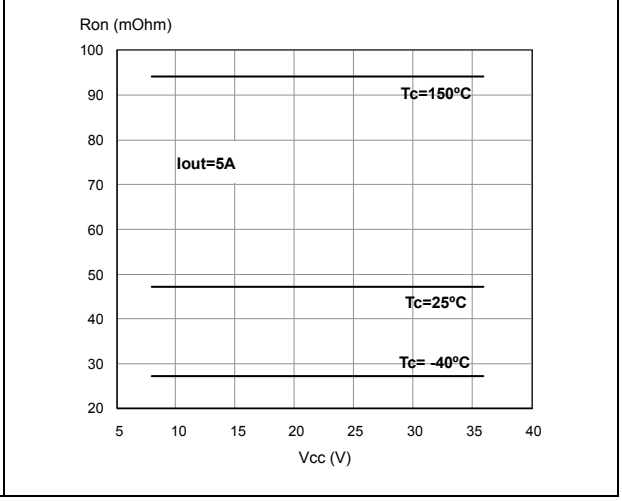
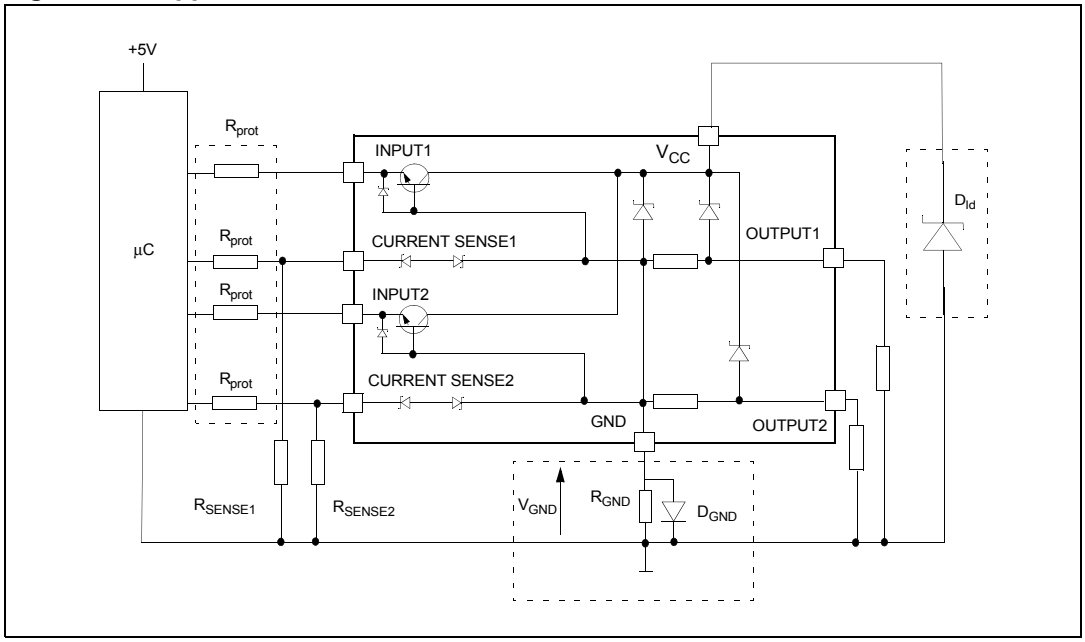


Figure 18. On-state resistance vs V_{CC}



3 Application information

Figure 19. Application schematic



3.1 GND protection network against reverse battery

3.1.1 Solution 1: resistor in the ground line (R_{GND} only)

This can be used with any type of load.

The following is an indication on how to dimension the R_{GND} resistor.

1. $R_{GND} \leq 600\ mV / I_{S(on)max}$
2. $R_{GND} \geq (-V_{CC}) / (-I_{GND})$

where $-I_{GND}$ is the DC reverse ground pin current and can be found in the absolute maximum rating section of the device's datasheet.

Power dissipation in R_{GND} (when $V_{CC} < 0$: during reverse battery situations) is:

$P_D = (-V_{CC})^2 / R_{GND}$

This resistor can be shared amongst several different HSDs. Please note that the value of this resistor should be calculated with formula (1) where $I_{S(on)max}$ becomes the sum of the maximum on-state currents of the different devices.

Please note that if the microprocessor ground is not shared by the device ground then the R_{GND} produces a shift ($I_{S(on)max} * R_{GND}$) in the input thresholds and the status output values. This shift varies depending on how many devices are ON in the case of several high-side drivers sharing the same R_{GND}.

If the calculated power dissipation leads to a large resistor or several devices have to share the same resistor then ST suggests to utilize solution 2 (see *Section 3.1.2*).

3.1.2 Solution 2: diode (D_{GND}) in the ground line

A resistor (R_{GND} = 1 kΩ) should be inserted in parallel to D_{GND} if the device drives an inductive load.

This small signal diode can be safely shared amongst several different HSDs. Also in this case, the presence of the ground network produces a shift (~600 mV) in the input threshold and in the status output values if the microprocessor ground is not common to the device ground. This shift does not vary if more than one HSD shares the same diode/resistor network.

Series resistor in INPUT and STATUS lines are also required to prevent that, during battery voltage transient, the current exceeds the absolute maximum rating.

Safest configuration for unused INPUT and STATUS pin is to leave them unconnected, while unused SENSE pin has to be connected to ground pin.

3.2 Load dump protection

D_{ld} is necessary (Voltage Transient Suppressor) if the load dump peak voltage exceeds the V_{CC} max DC rating. The same applies if the device is subject to transients on the V_{CC} line that are greater than the ones shown in *Table 11*.

3.3 MCU I/Os protection

If a ground protection network is used and negative transient are present on the V_{CC} line, the control pins are pulled negative. ST suggests to insert a resistor (R_{prot}) in line to prevent the microcontroller I/Os pins to latch-up.

The value of these resistors is a compromise between the leakage current of microcontroller and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of microcontroller I/Os.

$-V_{CCpeak}/I_{latchup} \leq R_{prot} \leq (V_{OH\mu C}-V_{IH}-V_{GND}) / I_{IHmax}$

Calculation example:

For V_{CCpeak} = -100 V and $I_{latchup} \geq$ 20 mA; $V_{OH\mu C} \geq$ 4.5 V

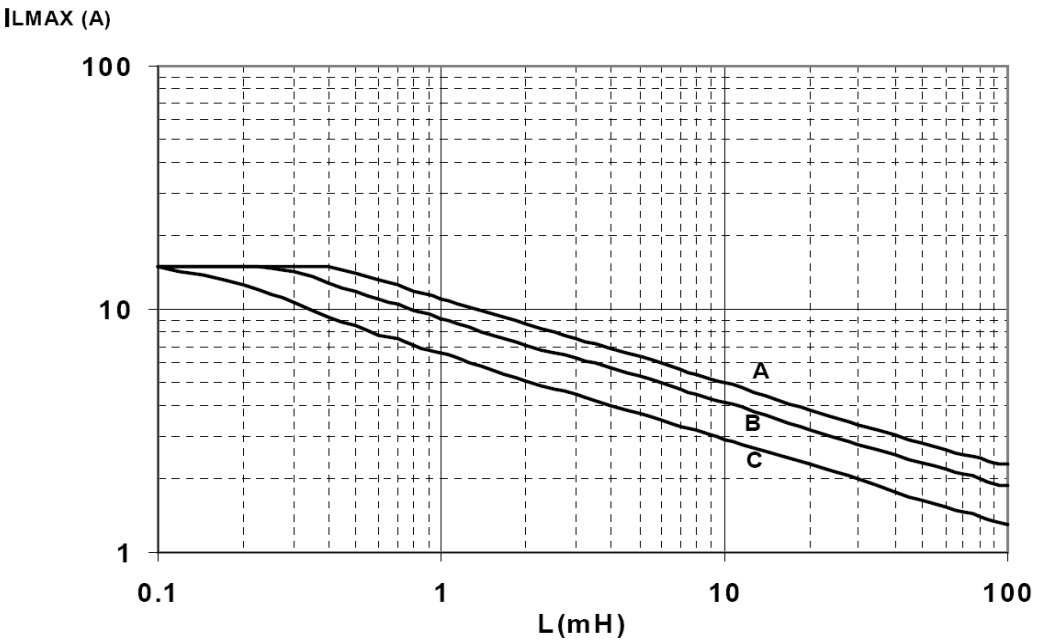
5 kΩ ≤ R_{prot} ≤ 65 kΩ.

Recommended values:

R_{prot} =10 kΩ.

3.4 PowerSO-10 maximum demagnetization energy (V_{CC} = 13.5 V)

Figure 20. Maximum turn- off current versus load inductance(1)

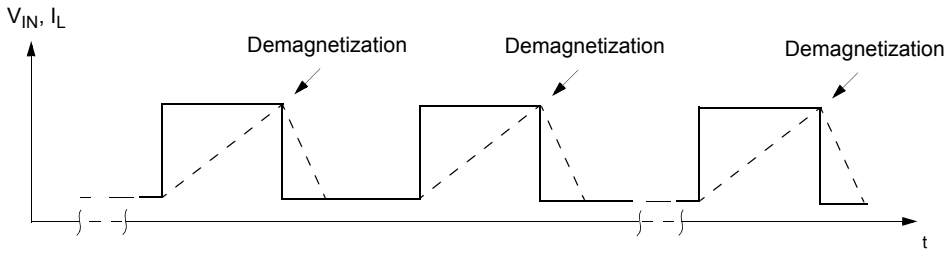


A: Single pulse at T_{jstart} = 150 °C

B: Repetitive pulse at T_{jstart} = 100 °C

C: Repetitive pulse at T_{jstart} = 125 °C

Condition:
V_{CC} = 13.5 V

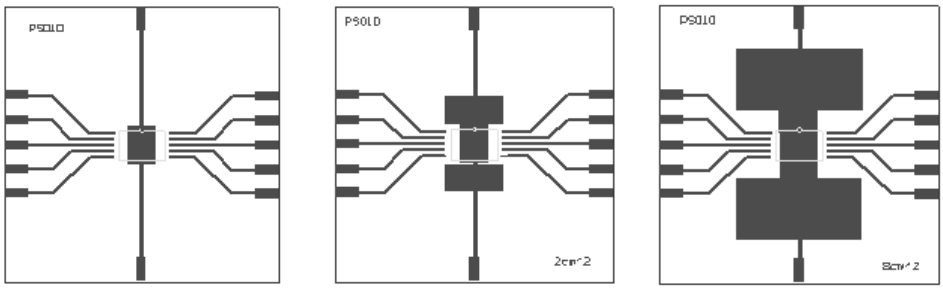


1. Values are generated with R_L = 0 Ω
In case of repetitive pulses, T_{jstart} (at beginning of each demagnetization) of every pulse must not exceed the temperature specified above for curves B and C.

4 Package and PCB thermal data

4.1 PowerSO-10 thermal data

Figure 21. PowerSO-10 PC board(1)



1. Layout condition of R_{th} and Z_{th} measurements (PCB FR4 area= 58 mm x 58 mm, PCB thickness=2 mm, Cu thickness = 35 µm, Copper areas: from minimum pad lay-out to 8 cm^2).

Figure 22. $R_{thj-amb}$ vs PCB copper area in open box free air condition

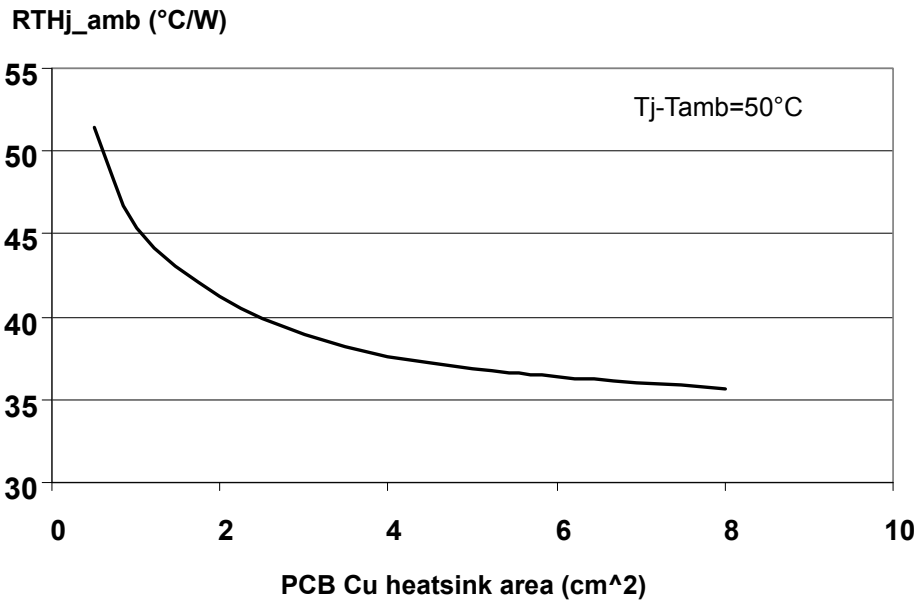
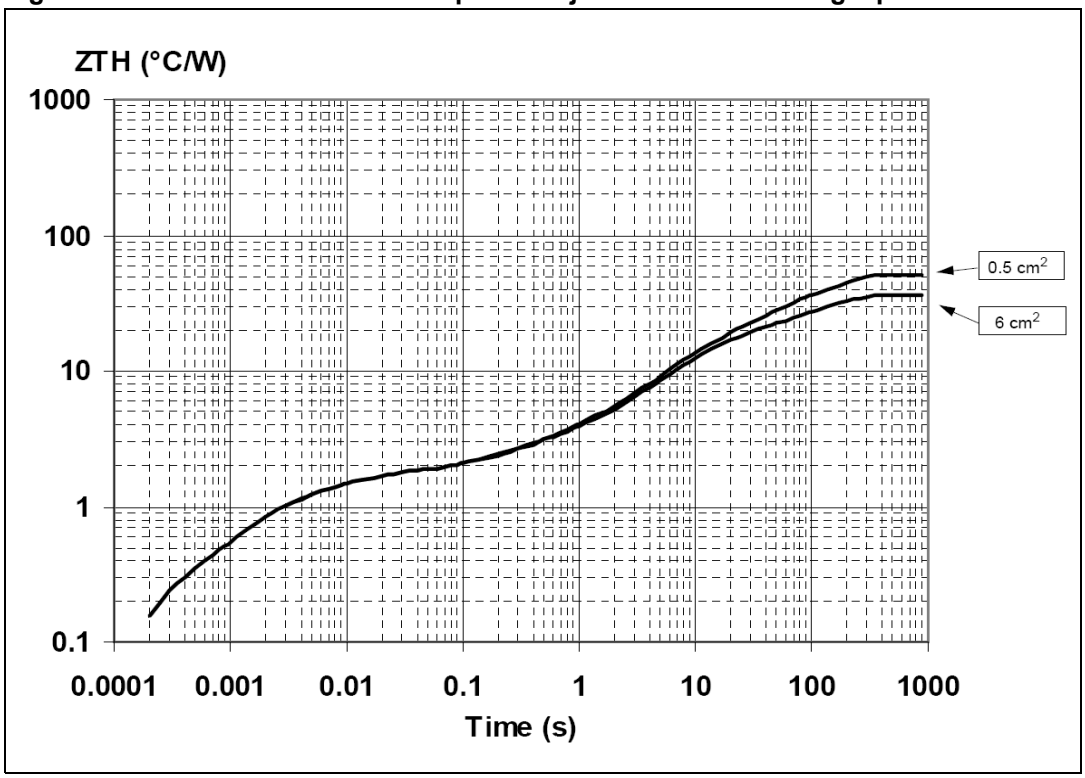


Figure 23. PowerSO-10 thermal impedance junction ambient single pulse



Equation 1: pulse calculation formula

$$Z_{TH\delta} = R_{TH} \cdot \delta + Z_{THtp}(1 - \delta)$$

where $\delta = t_p / T$

Figure 24. Thermal fitting model of a double channel HSD in PowerSO-10

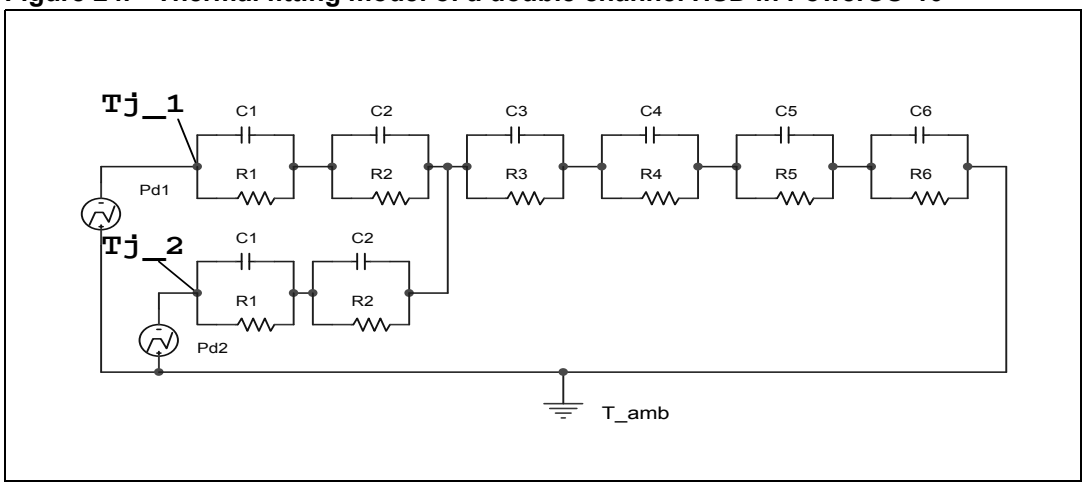


Table 14. Thermal parameter

Area/island (cm^2)	0.5	6
R1 (°C/ W)	0.15	
R2 (°C/ W)	0.8	
R3 (°C/ W)	0.7	
R4 (°C/ W)	0.8	
R5 (°C/ W)	12	
R6 (°C/ W)	37	22
C1 (W.s/ °C)	0.0006	
C2 (W.s /°C)	2.10E-03	
C3 (W.s/ °C)	0.013	
C4 (W.s/ °C)	0.3	
C5 (W.s/ °C)	0.75	
C6 (W.s/ °C)	3	5

5 Package and packing information

5.1 ECOPACK® packages

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

5.2 PowerSO-10 mechanical data

Figure 25. PowerSO-10 package dimensions

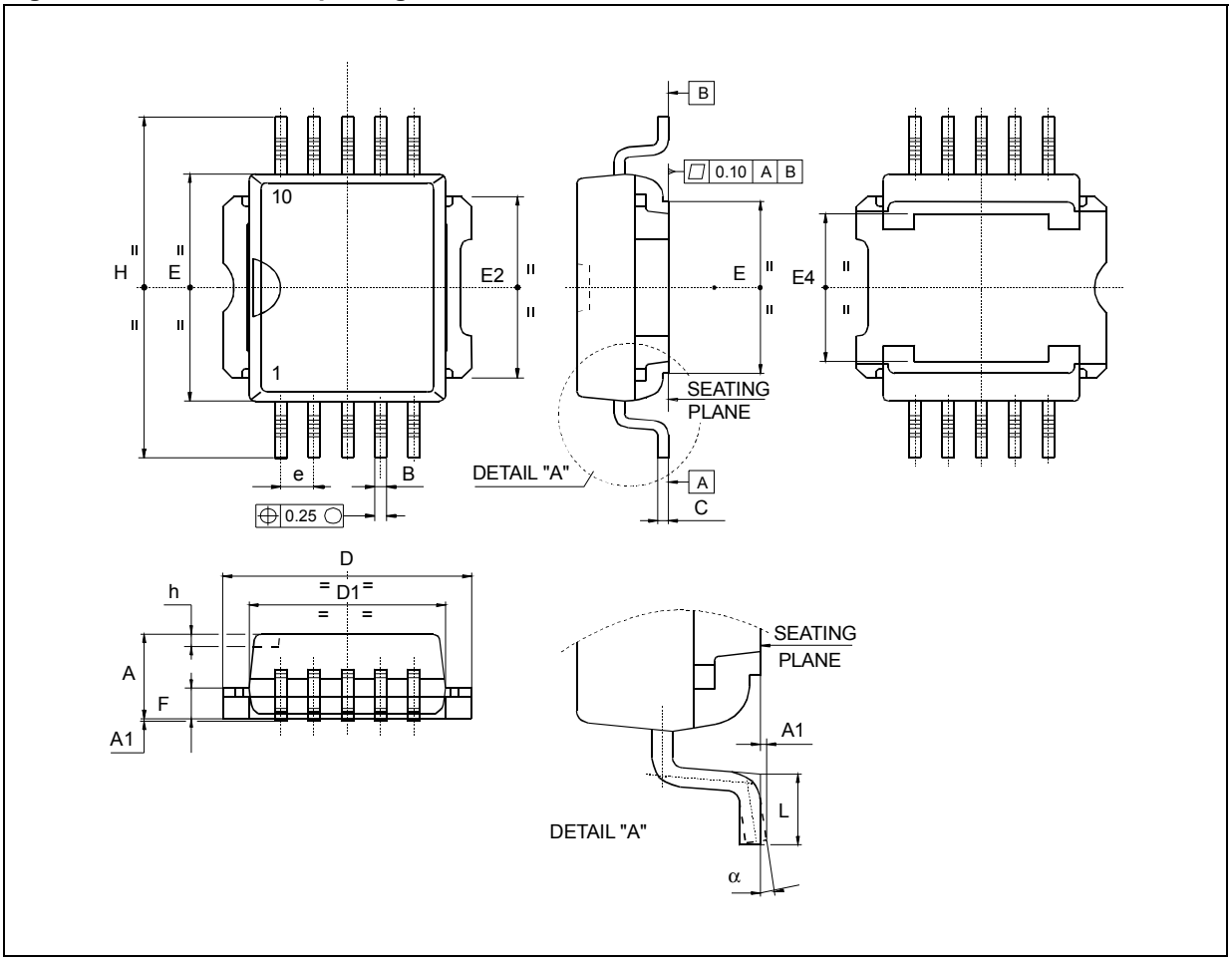


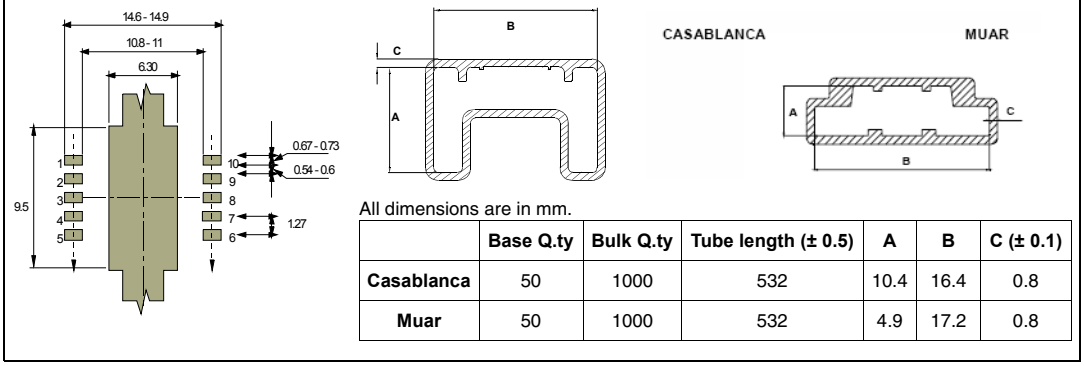
Table 15. PowerSO-10 mechanical data

Dim.	Millimeters		
	Min.	Typ.	Max.
A	3.35		3.65
A(1)	3.4		3.6
A1	0		0.10
B	0.40		0.60
B(1)	0.37		0.53
C	0.35		0.55
C(1)	0.23		0.32
D	9.40		9.60
D1	7.40		7.60
E	9.30		9.50
E2	7.20		7.60
E2(1)	7.30		7.50
E4	5.90		6.10
E4(1)	5.90		6.30
e		1.27	
F	1.25		1.35
F(1)	1.20		1.40
H	13.80		14.40
H(1)	13.85		14.35
h		0.50	
L	1.20		1.80
L(1)	0.80		1.10
α	0°		8°
α(1)	2°		8°

1. Muar only POA P013P.

5.3 PowerSO-10 packing information

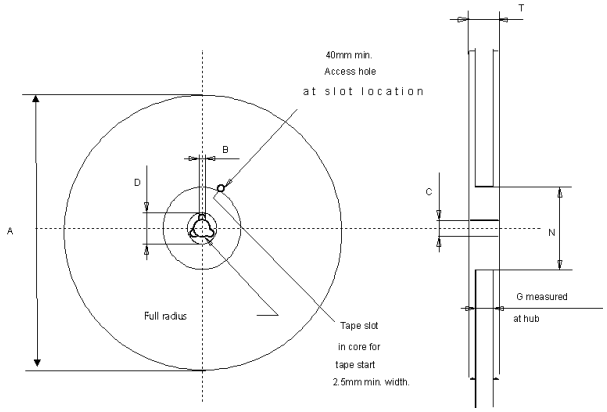
Figure 26. PowerSO-10 suggested pad layout and tube shipment (no suffix)



All dimensions are in mm.

	Base Q.ty	Bulk Q.ty	Tube length (± 0.5)	A	B	C (± 0.1)
Casablanca	50	1000	532	10.4	16.4	0.8
Muar	50	1000	532	4.9	17.2	0.8

Figure 27. Tape and reel shipment (suffix "TR")



REEL DIMENSIONS

Base Q.ty	600
Bulk Q.ty	600
A (max)	330
B (min)	1.5
C (± 0.2)	13
F	20.2
G (+ 2 / -0)	24.4
N (min)	60
T (max)	30.4

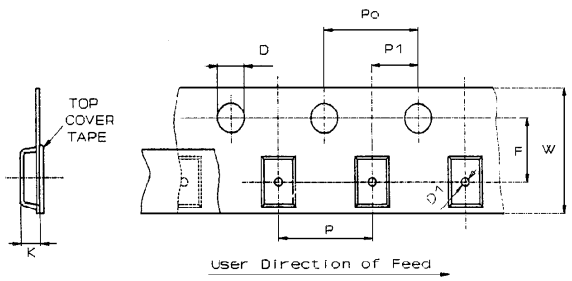
All dimensions are in mm.

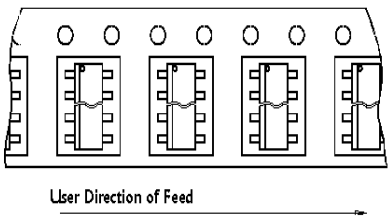
TAPE DIMENSIONS

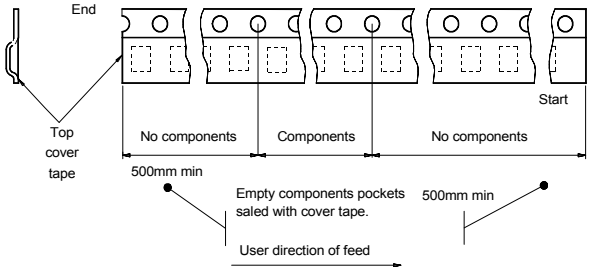
According to Electronic Industries Association (EIA) Standard 481 rev. A, Feb. 1986

Tape width	**W**	24
Tape Hole Spacing	**P0 (± 0.1)**	4
Component Spacing	**P**	24
Hole Diameter	**D (± 0.1/-0)**	1.5
Hole Diameter	**D1 (min)**	1.5
Hole Position	**F (± 0.05)**	11.5
Compartment Depth	**K (max)**	6.5
Hole Spacing	**P1 (± 0.1)**	2

All dimensions are in mm.







6 Revision history

Table 16. Document revision history

Date	Revision	Changes
19-Jul-2010	1	Initial release.
19-Sep-2013	2	Updated Disclaimer

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